TOSHIBA Transistor Silicon NPN Epitaxial Type

2SC3225

Switching Applications Solenoid Drive Applications

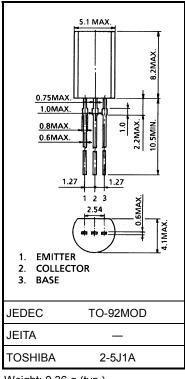
- High DC current gain: $h_{FE} = 500$ (min) (IC = 400 mA)
- Low collector-emitter saturation voltage: VCE (sat) = 0.5 V (max)(IC = 300 mA)

Maximum Ratings (Ta = 25°C)

Characteristics	Symbol	Rating	Unit
Collector-base voltage	V_{CBO}	40	V
Collector-emitter voltage	V _{CEO}	40	V
Emitter-base voltage	V _{EBO}	7	V
Collector current	I _C	2	Α
Base current	ΙΒ	0.5	Α
Collector power dissipation	PC	900	mW
Junction temperature	Tj	150	°C
Storage temperature range	T _{stg}	-55 to 150	°C

Industrial Applications

Unit: mm

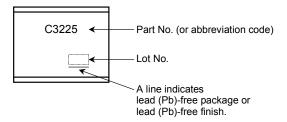


Weight: 0.36 g (typ.)

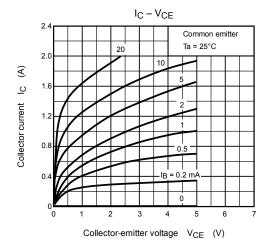
Electrical Characteristics (Ta = 25°C)

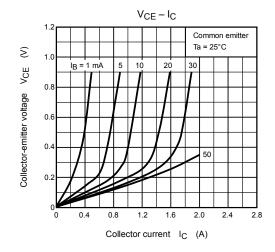
Chara	acteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Collector cut-off of	urrent	I _{CBO}	V _{CB} = 40 V, I _E = 0	_	_	10	μA
Emitter cut-off cu	rrent	I _{EBO}	V _{EB} = 7 V, I _C = 0	_	_	1	μA
Collector-emitter	breakdown voltage	V (BR) CEO	I _C = 10 mA, I _B = 0	40	_	_	V
DC current gain		h _{FE}	V _{CE} = 1 V, I _C = 400 mA	500	_	_	
Collector-emitter	saturation voltage	V _{CE (sat)}	I _C = 300 mA, I _B = 1 mA	_	0.3	0.5	V
Base-emitter satu	ration voltage	V _{BE (sat)}	I _C = 300 mA, I _B = 1 mA	_	_	1.1	V
Transition frequency		f _T	V _{CB} = 2 V, I _C = 100 mA	_	220	_	MHz
Collector output capacitance		C _{ob}	V _{CB} = 10 V, I _B = 0, f = 1 MHz	_	20	_	pF
Switching time Store	Turn-on time	t _{on}	20 μ s Input $ _{B_1}$ Output $ _{B_2}$ $ _{B_1}$ $ _{B_2}$ $ _{$	_	1.0	_	
	Storage time	t _{stg}		_	3.0	_	μs
	Fall time	t _f		_	1.2	_	

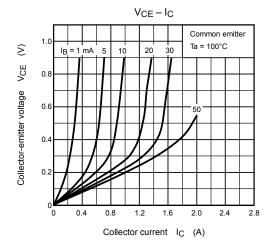
Marking

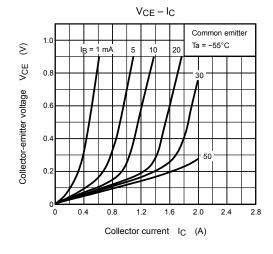


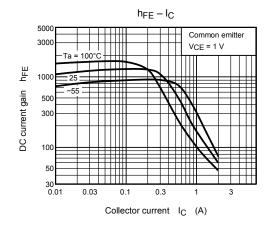
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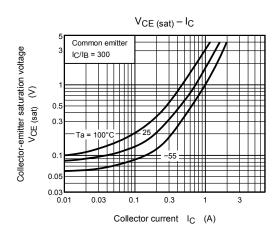


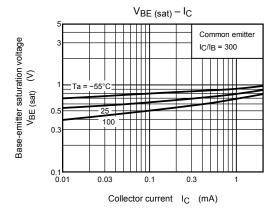


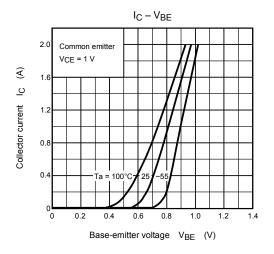


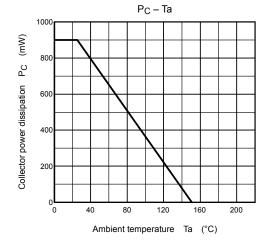


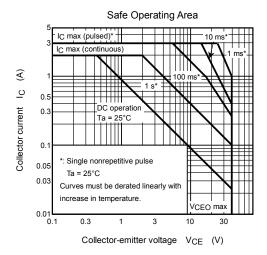












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